

Notice of References Cited	Application/Control No. 10/076,964	Applicant(s)/Patent Under Reexamination CATTELL ET AL.	
	Examiner Blaine Basom	Art Unit 2173	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Eisen, Michael. "ScanAlyze User Manual." Stanford University. 1999.
	V	Buhler et al. "Dapple: Improved Techniques for Finding Spots on DNA Microarrays." UW CSE Technical Report. 2000.
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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